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# **Proton Damage in Optocouplers**

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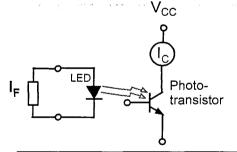
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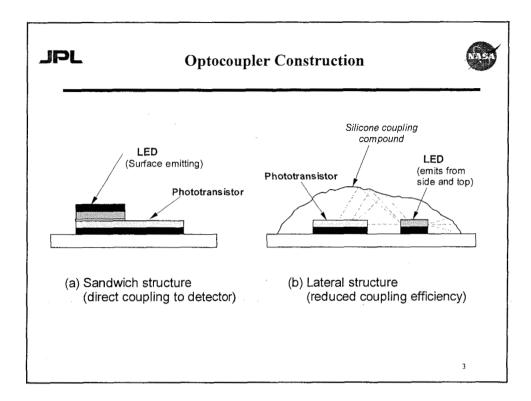
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# **Basic Properties of Optocouplers**





Current Transfer Ratio =  $\frac{I_C}{I_F}$ 



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# **Common Optocoupler Types**

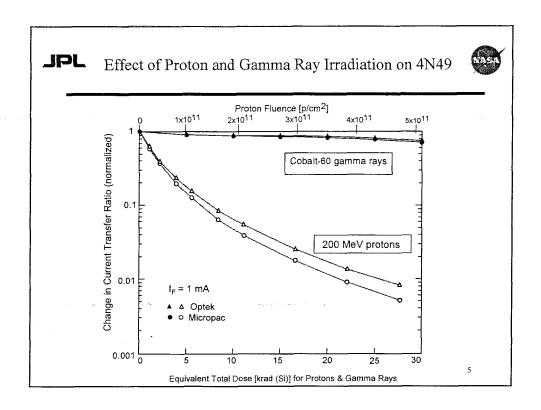


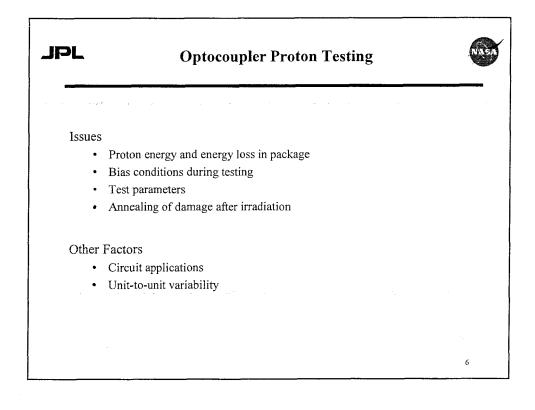
### 4N49

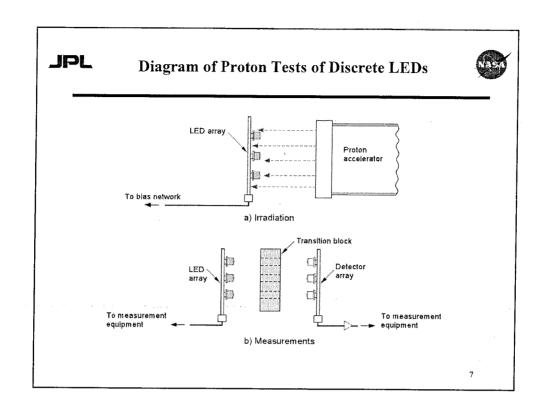
- Basic optocoupler with CTR<sub>min</sub> = 2
- Extremely sensitive to proton displacement damage effects
- · Caused by amphoterically doped LED technology

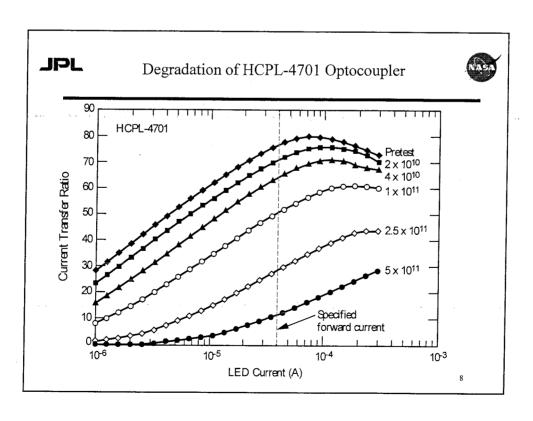
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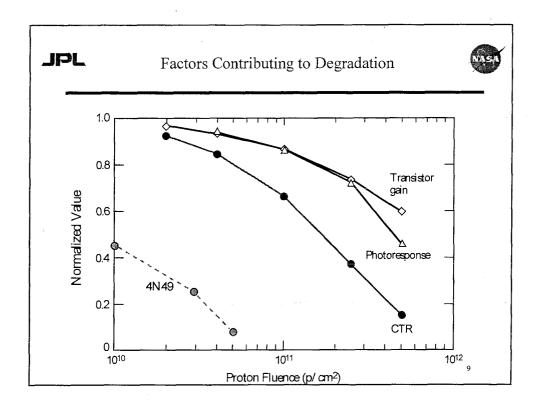
- High speed optocoupler with digital output;  $CTR_{min} = 10$
- Uses different LED technology that eliminates extreme sensitivity to proton damage
- Sensitive to transients from protons and heavy ions
- Requires standby power for digital circuitry













# **Other Factors**



# Proton Energy Is Important

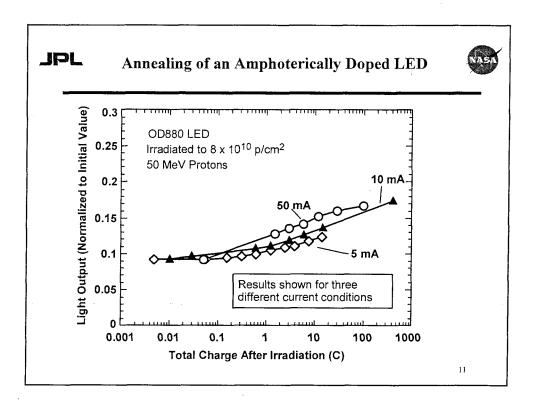
- Non-ionizing energy loss is uncertain for energies above 65 MeV
- Tests at energies below 65 MeV are recommended
   Near peak in energy spectrum for most systems (after shielding)
   Tests at high energies introduce errors in interpretation
   Displacement in silicon and III-V elements can contribute to degradation
- Damage needs to be related to energy spectrum in application

#### Annealing Is a Potential Interference for Optocoupler Testing

- Biasing devices for extended periods prior to and after irradiation will markedly reduce the measured damage
- Injected current during measurements can also cause significant recovery

# Optocouplers Are Hybrid Devices

- · Particularly affected by LED technology
- No explicit control over LEDs in device specifications





# **Other Issues**



Optocouplers Are also Sensitive to Transients

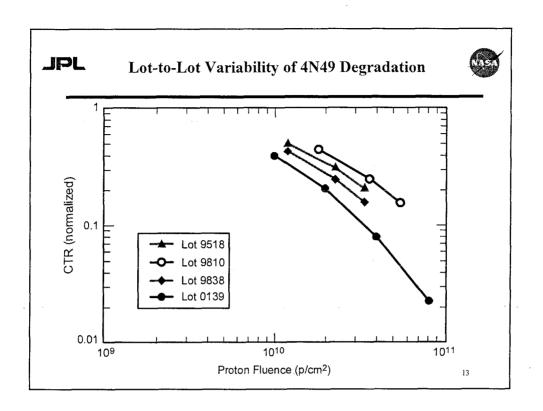
- · Problem is more severe for devices with high-speed amplifiers
- Caused upsets in Hubble Space Telescope

Aging and Temperature Effects Must Be Included

Possibility of Degradation in Coupling Material

Damage in LEDs Is Superlinear with Fluence

- Must be taken into account in interpreting radiation data
- Affects design margins
- "Amplifies" degradation in devices with low initial CTR



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# Conclusions



### Optocouplers Are Widely Used in Space Systems

- Radiation testing must include tests with high-energy protons
- Some devices are extremely sensitive to proton damage
- New types of optocouplers are available that are much less affected by radiation compared to older optocoupler types

### Testing Is More Complex than for Conventional Electronic Devices

- Strong energy dependence of proton damage
- · Interference from annealing during irradiation or measurements
- Wider variability in responses because of mechanical issues with optical path